

L Number	Hits	Search Text	DB	Time stamp
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2	17	("4253768" "4587617" "5129009" "5210041" "5219765" "5240866" "5301248" "5325445" "5426506" "5434790" "5440649" "5479252" "5801965" "5923430" "5982921" "6014461" "6021380").PN.	USPAT	2003/03/03 17:02
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3	2	("5801965" "6438438" "6177287" "5943437" "6347150" "5659172" "5917935" "5966459" "4532650" "5325445" "6222935" "6222935" "6104835" "4587617" "6456899" "5513275" "5394481" "5204910" "4449818" "6167150" "6334097" "4173441" "5734742" "5862055" "5798830" "6466895" "5414270" "5515159" "6057926" "6092059" "6171874" "5263094" "5745239" "6200823" "5253306" "4989258" "6353222" "5602646" "5335293" "6341241" "6473665" "4308959" "6166393" "5808735" "5761337" "6259960" "6185511" "6233352" "5182775" "5844603").pn.) and (short adj defects)	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:34
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4	0	"circuit pattern short defects"	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:35
5	0	"circuit pattern open defects"	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:36
6	23627	semiconductor and inspection	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:37
7	741	(semiconductor and inspection) and classification	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:37
8	3	((semiconductor and inspection) and classification) and reclassification	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:49
9	7	5946213.URPN.	USPAT	2003/03/03 17:44
11	387	209/44.1	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:49
12	543	209/571	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:49
13	563	209/573	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:49
10	70	209/44.4	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:50
14	75528	209/\$.ccls.	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:51
15	349	209/\$.ccls. and semiconductor	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:51
16	91	(209/\$.ccls. and semiconductor) and inspection	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:59
17	374	382/152	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 18:00

18	693	382/149	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 18:00
19	221	382/149 and short	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 18:00
20	8	(382/149 and short) and (short adj defect)	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 18:12
21	7	(semiconductor and inspection) and (kill adj ratio)	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 19:28
22	4	"6338001"	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 19:28

L Number	Hits	Search Text	DB	Time stamp
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2	17	("4253768" "4587617" "5129009" "5210041" "5219765" "5240866" "5301248" "5325445" "5426506" "5434790" "5440649" "5479252" "5801965" "5923430" "5982921" "6014461" "6021380").PN.	USPAT	2003/03/03 17:02
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3	2	("5801965" "6438438" "6177287" "5943437" "6347150" "5659172" "5917935" "5966459" "4532650" "5325445" "6222935" "6222935" "6104835" "4587617" "6456899" "5513275" "5394481" "5204910" "4449818" "6167150" "6334097" "4173441" "5734742" "5862055" "5798830" "6466895" "5414270" "5515159" "6057926" "6092059" "6171874" "5263094" "5745239" "6200823" "5253306" "4989258" "6353222" "5602646" "5335293" "6341241" "6473665" "4308959" "6166393" "5808735" "5761337" "6259960" "6185511" "6233352" "5182775" "5844603").pn.) and (short adj defects)	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:34
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6	23627	semiconductor and inspection	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:37
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9	7	5946213.URPN.	USPAT	2003/03/03 17:44
11	387	209/44.1	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:49
12	543	209/571	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:49
13	563	209/573	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:49
10	70	209/44.4	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:50
14	75528	209/\$.ccls.	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:51
15	349	209/\$.ccls. and semiconductor	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:51
16	91	(209/\$.ccls. and semiconductor) and inspection	USPAT; EPO; JPO; DERWENT; USOCR	2003/03/03 17:51